

UNITED STATES PATENT AND TRADEMARK OFFICE  
CERTIFICATE OF CORRECTION

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PATENT NO.: 6803248 *B2*  
APPLICATION NO: 10/029093  
DATE: ~~12/12/2004~~ *Oct. 12, 2004*  
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It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

After Claim 5, insert dependent claims 36-42 which were added in an Amendment dated January 5, 2004

36. The method of claim 24, wherein the volumetric ratio of H<sub>2</sub>O to HCl in the solution is greater than about 15:1.
37. The method of claim 24, wherein the volumetric ratio of H<sub>2</sub>O to HCl in the solution is at least about 20:1.
38. The method of claim 36, wherein the mole ratio of H<sub>2</sub>O<sub>2</sub> to HCl in the solution is within the range of about 1:12 to about 3:4.
39. The method of claim 36, wherein the mole ratio of H<sub>2</sub>O<sub>2</sub> to HCl in the solution is within the range of about 1:12 to about 1:4.
40. The method of claim 37, wherein the mole ratio of H<sub>2</sub>O<sub>2</sub> to HCl in the solution is within the range of about 1:12 to about 3:4.
41. The method of claim 37, wherein the mole ratio of H<sub>2</sub>O<sub>2</sub> to HCl in the solution is within the range of about 1:12 to about 1:4.
42. The method of claim 29, wherein the composition is selective to InGaP.

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